

AWAD2012 (Okinawa Seinen-kaikan, Naha, June 27-29)

Wed, June 27		
8:00		
	Opening Address (8:45 – 8:55) Room A	
9:00	Plenary Session (8:50 – 10:50) Room A	
10:00		
11:00		
	Short Break (10 min.)	
	Si-based Power Device Technology (11:00 – 12:00) Room A	Detectors and Sensors (11:00 –12:15) Room B
12:00		
	Lunch Break (12:15–13:15, 60 min.)	
13:00		
	MOSFETs and Memory Technology (13:15 – 15:15) Room A	Interconnects and Integration Technologies (13:15 – 15:00) Room B
14:00		
15:00	Break (30 min.)	Break (15 min.)
	TFT Technology I (15:30 – 17:00) Room A	Circuit Technology I (15:15– 17:00) Room B
16:00		
17:00	Break (30 min.)	Break (15 min.)
	TFT Technology II (17:15 – 18:45) Room C	Circuit Technology II (17:15 – 19:00) Room B
18:00		
19:00		

Room A (Hall)
 Room B (2F)
 Room C (1F)

Thu, June 28	
8:00	
9:00	Memory Technology (8:30 – 10:15) Room A
	Energy Harvesting (8:30 – 9:45) Room B
10:00	Gate Stack Technology (9:45 – 10:30) Room B
	Break (25 min.)
	Break (10 min.)
11:00	Poster session (10:40–12:00) Room A
12:00	
Lunch Break (12:00–13:00, 60 min.)	
13:00	
14:00	Excursion (13:00–18:00)
15:00	
16:00	
17:00	
18:00	Banquet (18:00–20:00) Room A
19:00	
20:00	

Fri, June 29	
8:00	
9:00	Advanced Si Technology (8:15 – 10:30) Room A
	Widegap and III-V Semiconductor Devices (8:15 – 10:30) Room B
10:00	
Break (15 min.)	
11:00	MOSFET Reliability (10:45 – 12:30) Room A
	Widegap and Nanowire Devices (10:45 – 12:15) Room B
12:00	
	Break (15 min.)
Closing session (12:30 – 12:40) Room A	